High Voltage Power MOSFET

N-Channel Enhancement Mode Fast Intrinsic Diode


| Symbol | Test Conditions | Maximum Ratings |  |
| :---: | :---: | :---: | :---: |
| $\mathrm{V}_{\text {DSs }}$ | $\mathrm{T}_{j}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}$ | 2500 | V |
| $\mathrm{V}_{\text {DGR }}$ | $\mathrm{T}_{J}=25^{\circ} \mathrm{C}$ to $150^{\circ} \mathrm{C}, \mathrm{R}_{\mathrm{GS}}=1 \mathrm{M} \Omega$ | 2500 | V |
| $\mathrm{V}_{\text {Gss }}$ | Continuous | $\pm 20$ | V |
| $\mathrm{V}_{\text {GSM }}$ | Transient | $\pm 30$ | V |
| $\mathrm{I}_{\mathrm{D} 25}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 1.5 | A |
| $\underline{\mathrm{I}_{\mathrm{DM}}}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$, Pulse Width Limited by $\mathrm{T}_{\mathrm{JM}}$ | 6 | A |
| $\mathrm{P}_{\mathrm{D}}$ | $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ | 250 | W |
| $\mathrm{T}_{\mathrm{J}}$ |  | - $55 \ldots+150$ | ${ }^{\circ} \mathrm{C}$ |
| TJM |  | 150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {stg }}$ |  | - $55 \ldots+150$ | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | 1.6 mm (0.062 in.) From Case for 10 s | 300 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\text {soLD }}$ | Plastic Body for 10s | 260 | ${ }^{\circ} \mathrm{C}$ |
| Weight |  | 4 | g |

## Features

- High Blocking Voltage
- High Voltage Package
- Fast Intrinsic Diode
- Low Package Inductance


## Advantages

- Easy to Mount
- Space Savings
- High Power Density



## Applications

- High Voltage Power Supplies
- Capacitor Discharge
- Pulse Circuits



## ADVANCE TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

Fig. 1. Output Characteristics $@ \mathrm{~T}_{\mathrm{J}}=@ 25^{\circ} \mathrm{C}$


Fig. 4. $R_{D S(o n)}$ Normalized to $I_{D}=0.5 \mathrm{~A}$ Value vs. Junction Temperature


Fig. 5. Maximum Drain Current vs.
Case Temperature


Fig. 2. Output Characteristics @ $\mathrm{T}_{\mathrm{J}}=125^{\circ} \mathrm{C}$


Fig. 3. $R_{D S(o n)}$ Normalized to $I_{D}=0.5 \mathrm{~A}$ Value vs. Drain Current


Fig. 6. Input Admittance


Fig. 7. Transconductance


Fig. 9. Gate Charge


Fig. 11. Forward-Bias Safe Operating Area
@ $T_{C}=25^{\circ} \mathrm{C}$


Fig. 8. Forward Voltage Drop of Intrinsic Diode


Fig. 10. Capacitance


Fig. 12. Forward-Bias Safe Operating Area
@ $\mathrm{T}_{\mathrm{C}}=75^{\circ} \mathrm{C}$


IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

Fig. 13. Maximum Transient Thermal Impedance


Disclaimer Notice - Information furnished is believed to be accurate and reliable. However, users should independently evaluate the suitability of and test each product selected for their own applications. Littelfuse products are not designed for, and may not be used in, all applications. Read complete Disclaimer Notice at www.littelfuse.com/disclaimer-electronics.

